

Supplementary Information

# Thickness dependence of electronic structure and optical properties of F8BT thin films

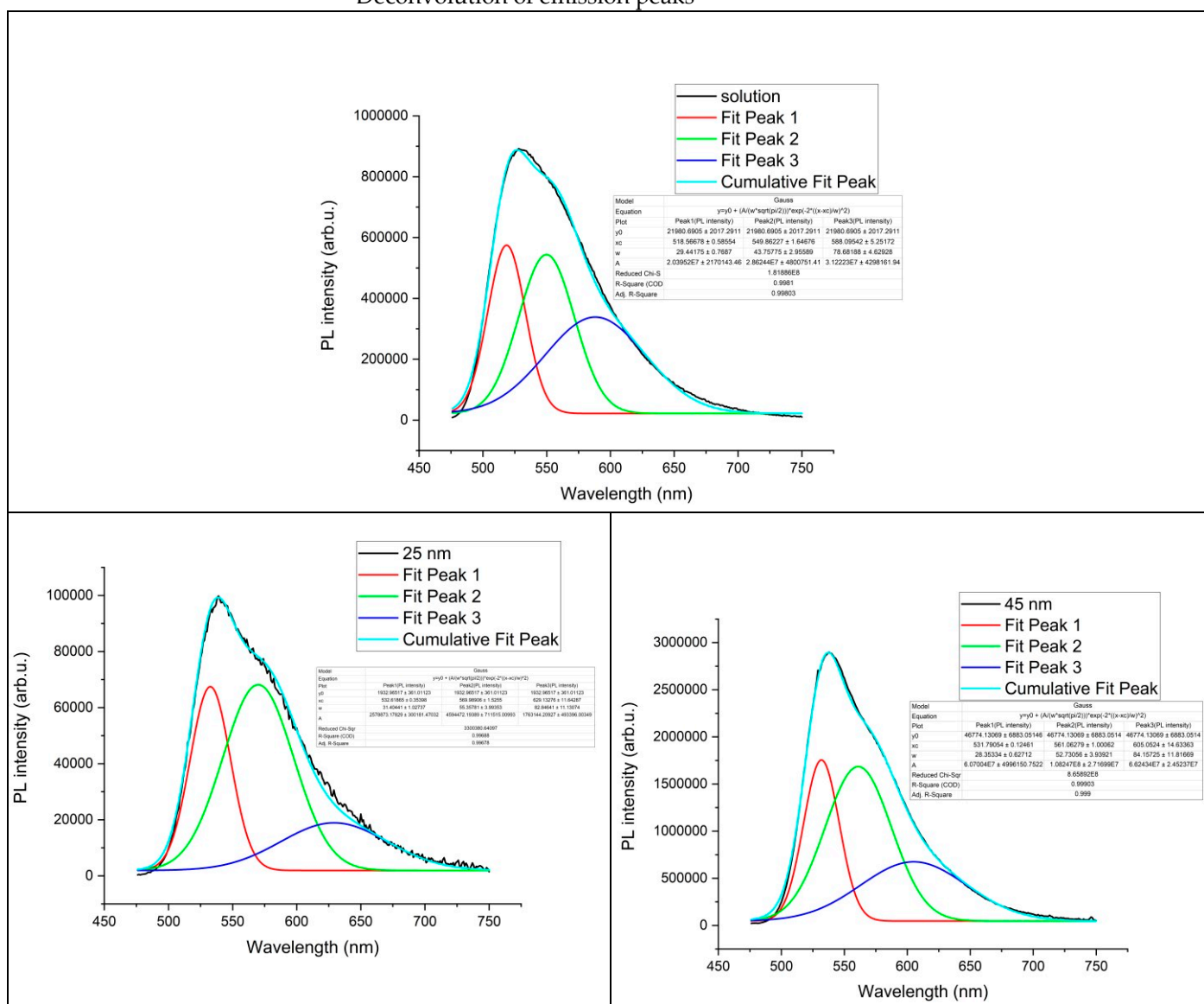
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## Deconvolution of emission peaks



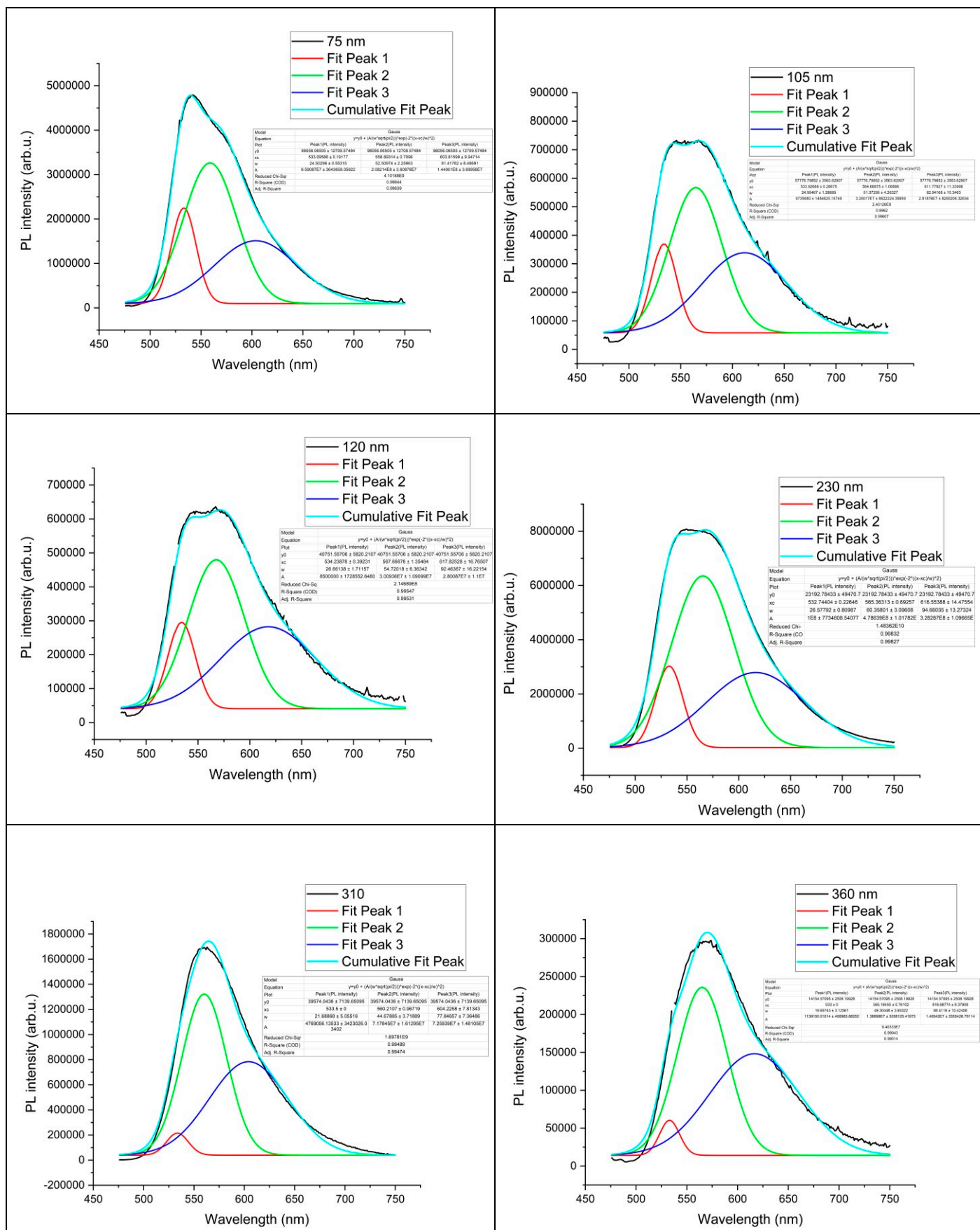
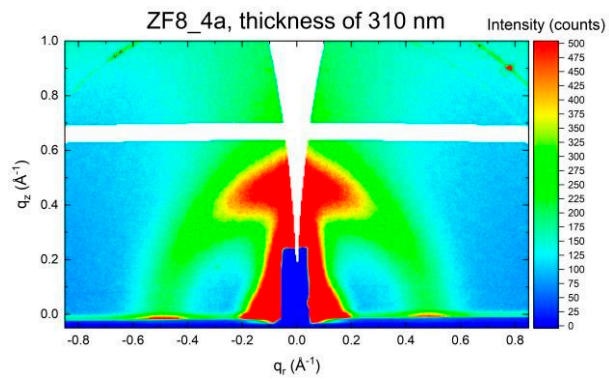
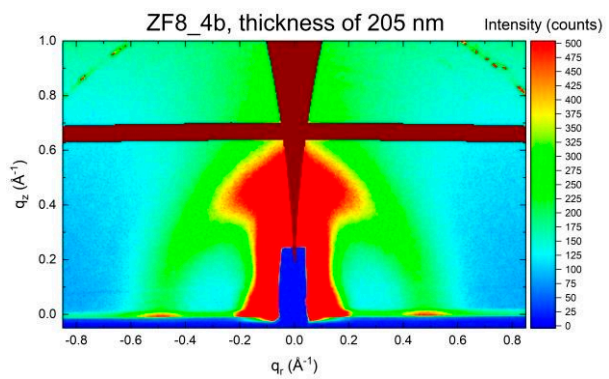
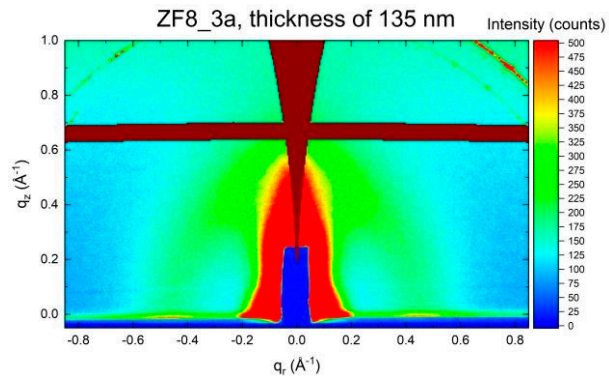
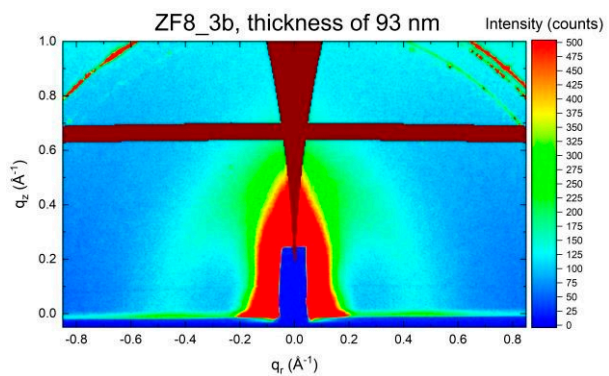
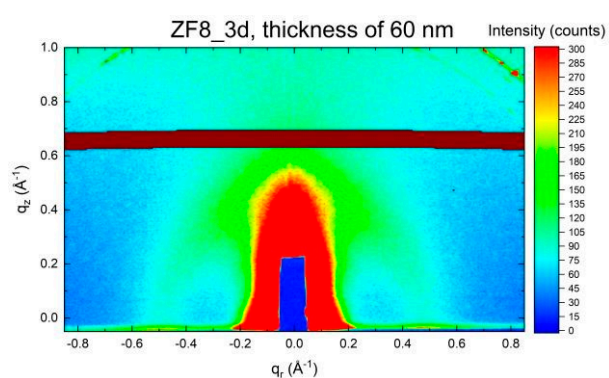
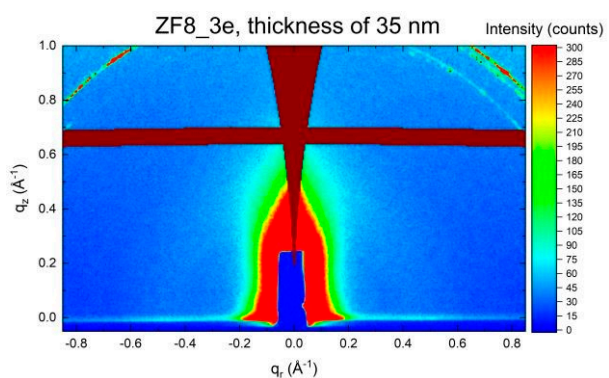
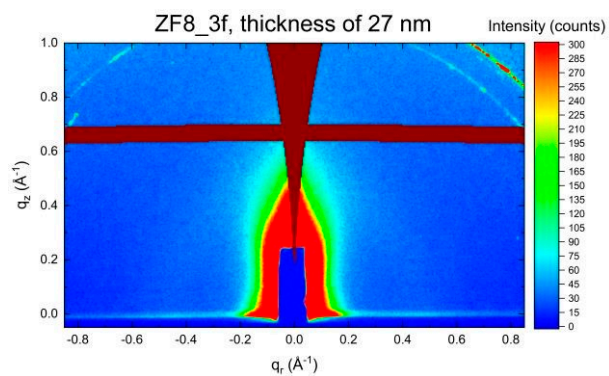


Figure S1 Deconvoluted PL emission peaks with their integrated areas.

# GIWAXS Patterns



**Figure S2** The GIWAXS pattern of polymer layers showing the integration area of the horizontal diffraction peaks along  $q_r$  axis (white rectangle) and the principle of integration of the vertical diffraction peak along  $q_z$  axis between  $\chi = -20^\circ$  and  $\chi = 20^\circ$ . 18